

A Comparative Analysis of Low Template (LT) DNA Testing
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Outline of Topics to Discuss

- Introduction to Low Template (LT) DNA
 - Brief description and historical perspective
- Challenges and Limitations of LT-DNA testing
 - Approaches to genotyping low template DNA
- Signal enhancement techniques: NIST data and results
 - Increasing PCR cycling with 3 extra cycles
 - MinElute PCR Purification Kit on PCR products
- Summary and conclusions

Some Definitions of Low Template (LT) DNA

- Working with **<100-200 pg genomic DNA**
- Considered to be data below stochastic threshold level where PCR amplification is not as reliable (determined by each laboratory; typically 150-250 RFUs)
- Enhancing the sensitivity of detection (increasing PCR cycles, PCR product clean-up, increasing CE injection/voltage)
- Having too few copies of DNA template to ensure reliable PCR amplification (allelic or full locus drop-out)
- Can often be the minor component of mixture samples consisting of low level DNA template amounts

LT-DNA is not a “new” technique...

- **1996** – Taberlet *et al.* describe “reliable genotyping of samples with very low DNA quantities using PCR”
- **1997** – Findlay *et al.* report single cell STR analysis
- **1999** – Forensic Science Service begins LT-DNA casework in UK (as an alternative to mtDNA)
- **2001** – Budowle and FBI co-authors urge caution with using LT-DNA
- **2005** – NY State Commission of Forensic Science with the recommendation of NY State DNA subcommittee approve NYC OCME to use protocols for LT-DNA testing

Low Template DNA Work

- **Early work on touched objects and single cells:**
 - van Oorschot, R. A. and Jones, M. K. (1997) DNA fingerprints from fingerprints. *Nature*. 387(6635): 767
 - Findlay, I., Taylor, A., Quirke, P., Frazier, R., and Urquhart, A. (1997) DNA fingerprinting from single cells. *Nature*. 389(6651): 555-556
- **Application to routine forensic casework was pioneered by the Forensic Science Service:**
 - Gill, P., Whitaker, J., Flaxman, C., Brown, N., and Buckleton, J. (2000) An investigation of the rigor of interpretation rules for STRs derived from less than 100 pg of DNA. *Forensic Sci. Int.* 112(1): 17-40
 - Whitaker, J. P., Cotton, E. A., and Gill, P. (2001) A comparison of the characteristics of profiles produced with the AMPFISTR SGM Plus multiplex system for both standard and low copy number (LCN) STR DNA analysis. *Forensic Sci. Int.* 123(2-3): 215-223
 - Gill, P. (2001) Application of low copy number DNA profiling. *Croatian Medical Journal* 42(3): 229-32

Previous Presentations on LT-DNA Issues

- AAFS Feb 2003 LCN workshop
- AAFS Feb 2006 Advanced Topics in STRs workshop
- MAAFS May 2006 LCN workshop
- NEAFS Nov 2007 Cutting Edge workshop
- MAAFS May 2009 Advanced Forensics DNA Concepts workshop
- Promega Oct 2009 Technical Leaders workshop

<http://www.cstl.nist.gov/biotech/strbase/NISTpub.htm#Presentations>

Challenges of LT-DNA Testing

Gill, P. (2001) Croatian Med. J. 42(3): 229-232

- Increased chance for contamination (want a sterile lab environment to reduce staff contamination)
- Data interpretation is more complicated (due to stochastic variation during PCR amplification):
 - Heterozygote peak imbalance
 - Allele drop-out
 - Allele drop-in
 - Increased stutter products

LT-DNA profiles should be interpreted with careful guidelines

Stochastic (Random) Effects with LT-DNA

When Combined with Higher Sensitivity Techniques

**Loss of True Signal
(False Negative)**

Heterozygote Peak Imbalance

Identifier, 30 pg DNA, 31 cycles

Allelic Drop-out

Identifier, 30 pg DNA, 31 cycles

**Gain of False Signal
(False Positive)**

Higher Stutter

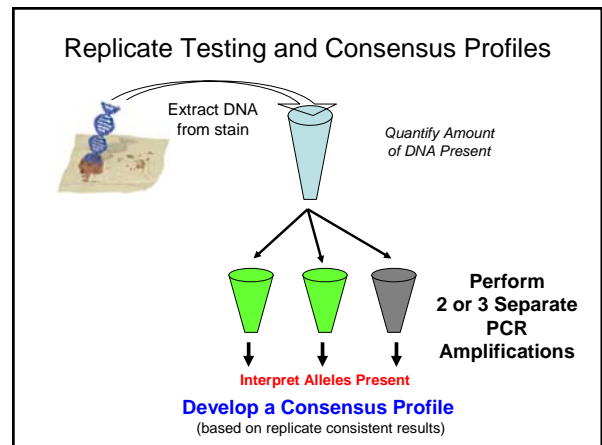
Identifier, 10 pg DNA, 31 cycles

Allelic Drop-in

Identifier, 10 pg DNA, 31 cycles

Suggestions for Optimal Results with LT-DNA

- Typically at least 2 – 3 PCR amplifications from the same DNA extract are performed to obtain **consensus profiles**
- An allele cannot be scored (considered real) unless it is present at least twice in replicate samples
- Extremely sterile environment is required for PCR setup to avoid contamination from laboratory personnel or other sources



Replicate LT-DNA Test Results from FSS

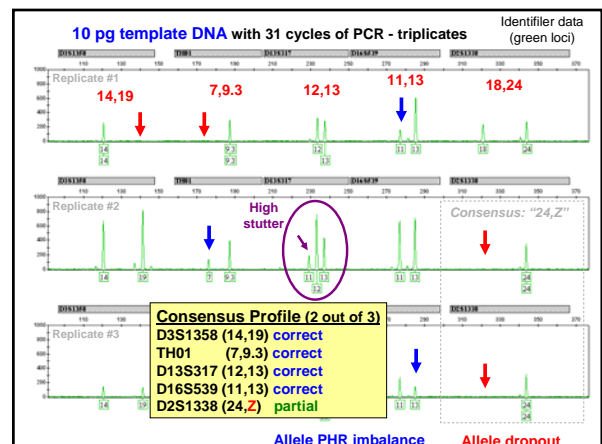
Gill, P. (2002) Role of short tandem repeat DNA in forensic casework in the UK--past, present, and future perspectives. BioTechniques 32(2): 366-385.

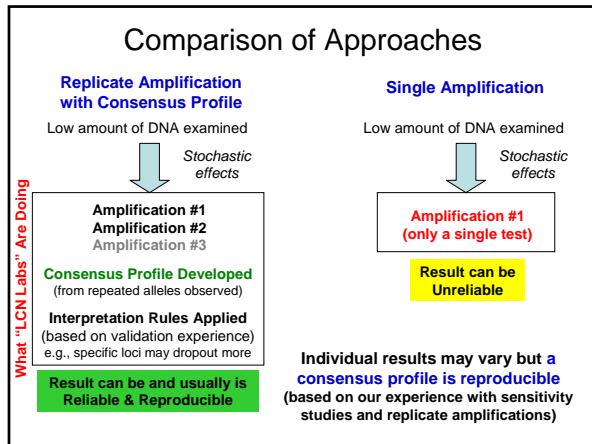
Table 2. Results of Six Replicate PCR Tests of a Sample Under Low Copy Number Analysis: Conditions Compared to the Control Sample

	Amelo	D19	D3	D8	THO	VWA	D21	FGA	D16	D18	D2
CONTROL	X X	14,14	18,18	15,15	7,9,3	19,19	28,32,2	20,23	9,12	12,16	17,23
Sample											
1	--	14 F*	--	15 F*	--	--	28,32,2	20 F*	--	16 F*	--
2	X F*	--	18 F*	15 F*	--	19 F*	--	--	12 F*	--	--
3	X F*	--	--	15 F*	--	--	--	--	--	--	17 F*
4	X F*	14 F*	18 F*	--	--	--	--	--	9,12	--	--
5	X F*	--	18 F*	--	--	18 F*	--	--	--	--	--
6	X F*	14 F*	--	--	--	19 F*	28,32,2	20 F*	--	12 F*	--
Consensus	X F*	14 F*	18 F*	15 F*	--	19 F*	28,32,2	20 F*	12 F*	--	--

The consensus result is reported, provided that an allele is observed at least twice. If only one allele is observed, then an F* designation is given to denote the possibility of allele drop-out.

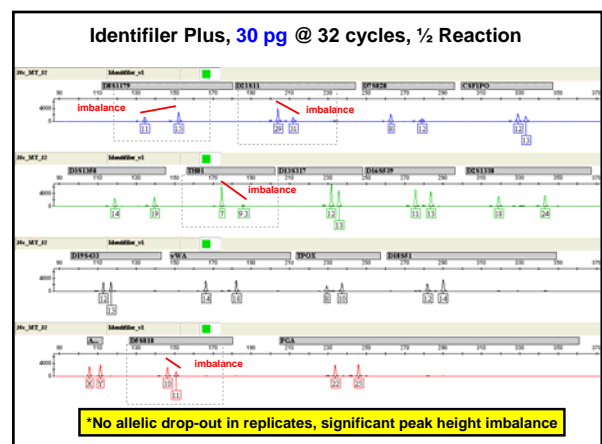
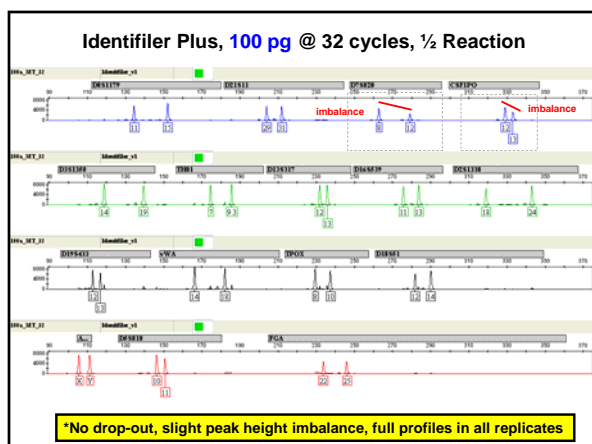
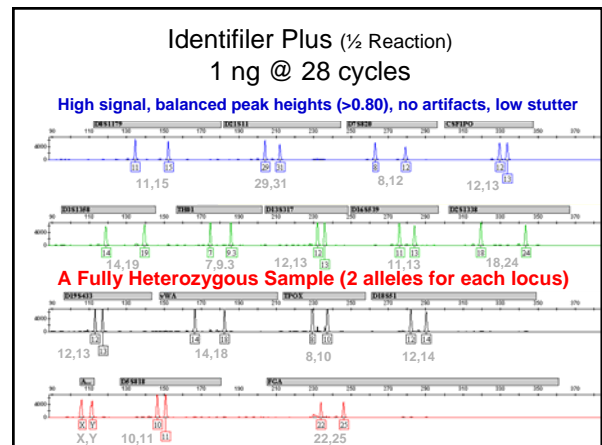
F* used to designate that allele drop-out of a second allele cannot be discounted when only a single allele is observed (OCME uses "Z")

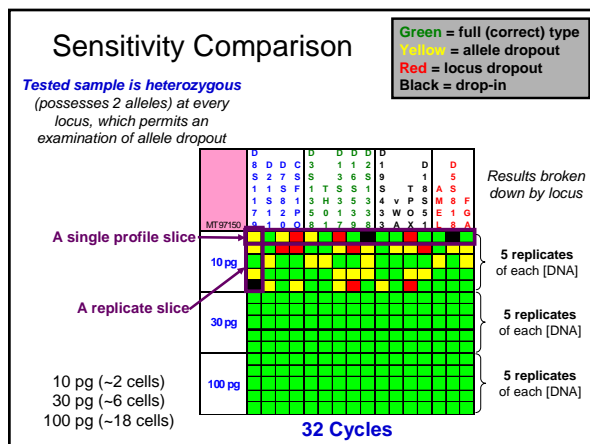
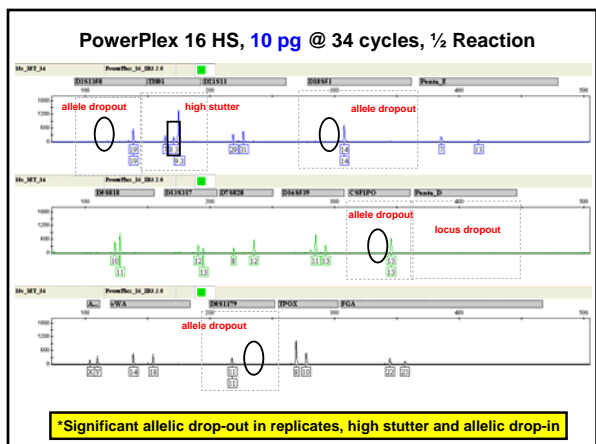
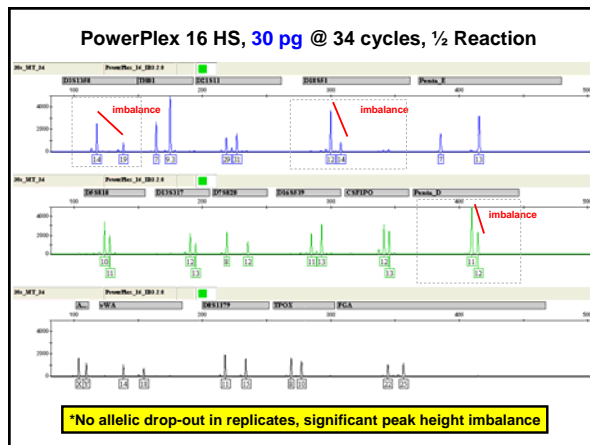
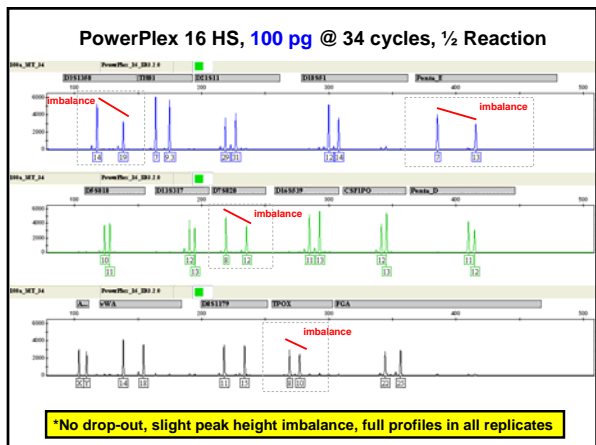
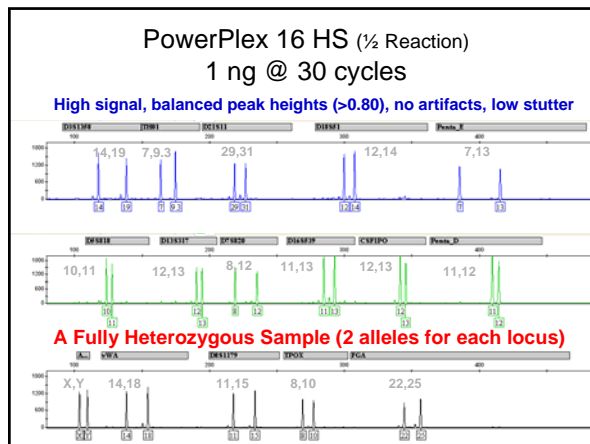
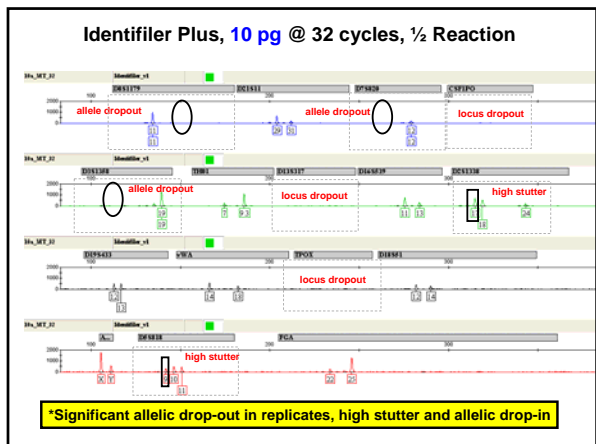


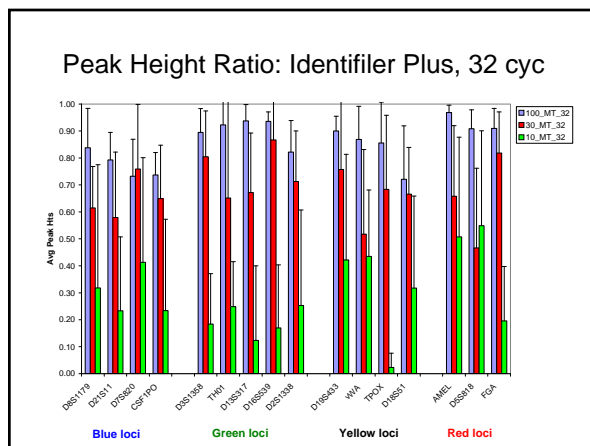
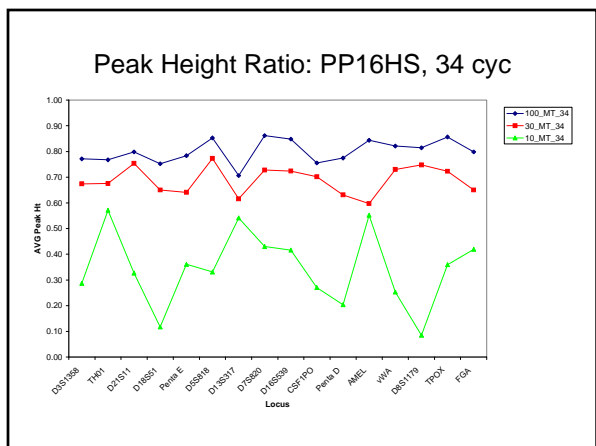
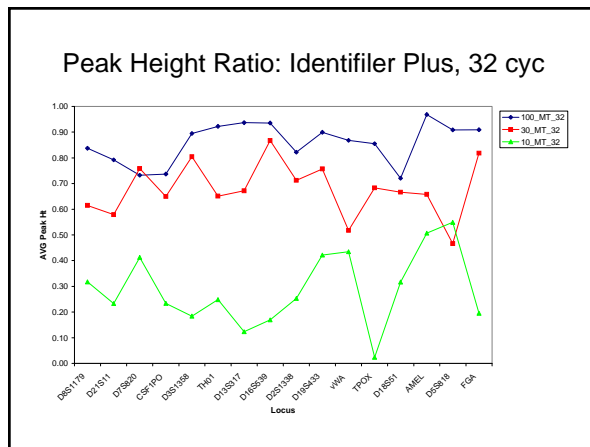
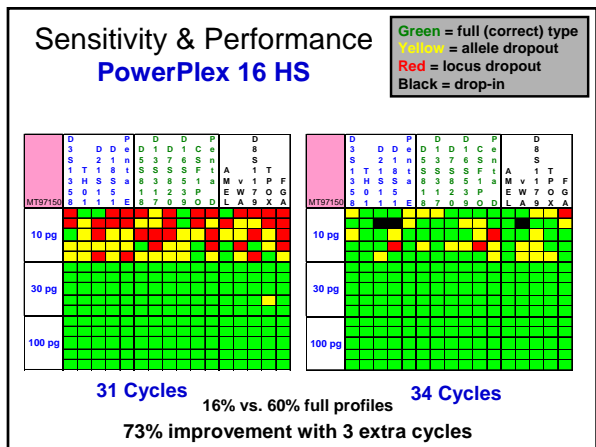
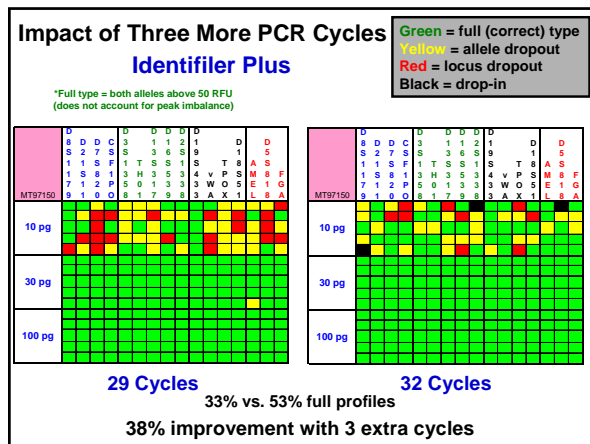
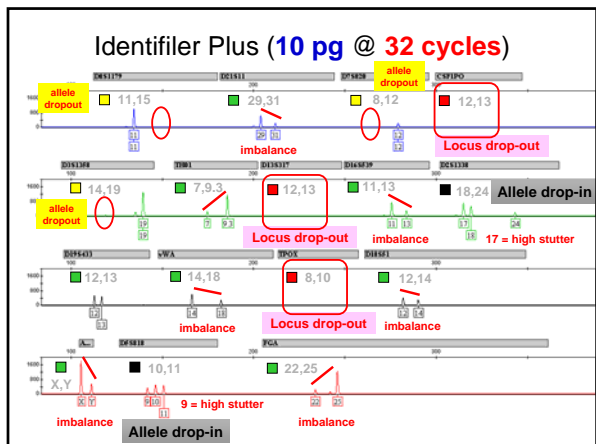


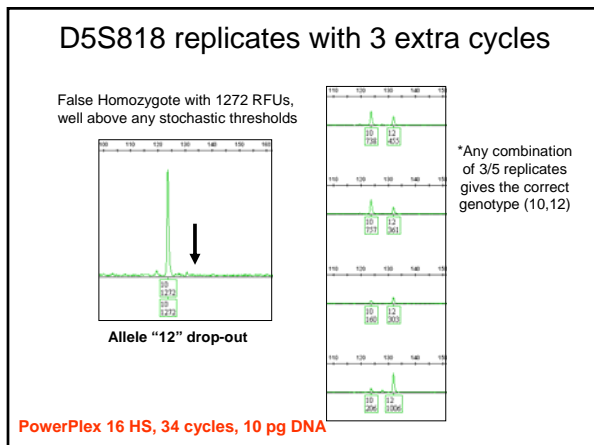
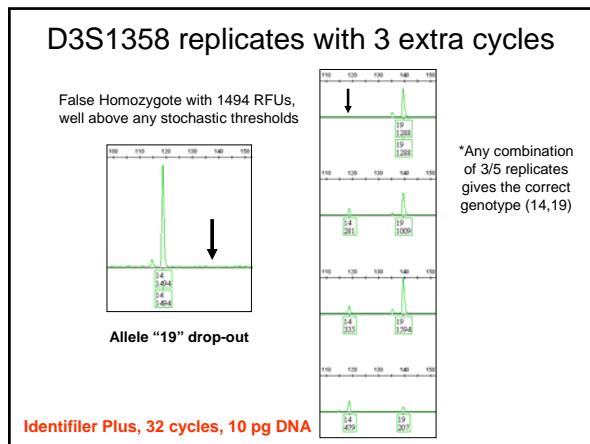
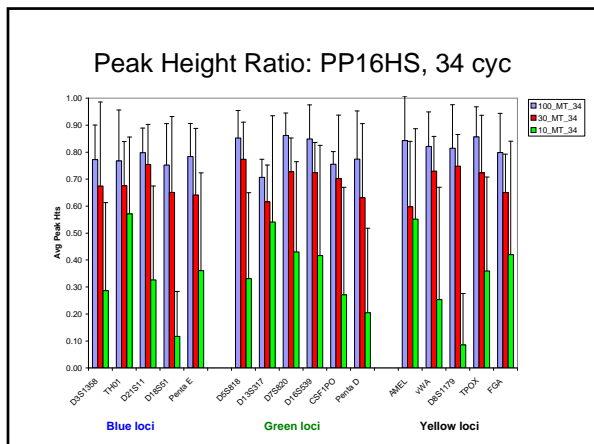
- ### Signal Enhancement Techniques
- **Additional PCR cycles**
 - **More sensitive kits** (Identifiler Plus and PowerPlex 16 HS)
 - **Microcon cleanup** to remove salts that interfere with electrokinetic injection (MinElute PCR Purification Kit from Qiagen)
 - Lower PCR volume (concentrates amplicon)
 - Increase TaqGold/enzyme concentration
 - Longer CE injection times and voltage
 - 10 s @ 3 kV = 30
 - 5 s @ 2 kV = 10

- ### Experimental Design to Study LT-DNA Issues
- **Pristine DNA Samples**
 - 2 single-source samples
 - **heterozygous for all loci tested** (permits peak height ratio studies)
 - **Low DNA Template Amounts**
 - Dilutions made after DNA quantitation against NIST SRM 2372
 - **100 pg, 30 pg, and 10 pg** (1 ng tested for comparison purposes)
 - **Replicates**
 - **5 separate PCR reactions** for each sample
 - **STR Multiplex Kits**
 - **Identifiler Plus and PowerPlex 16 HS** (half-reactions)
 - **Increased Cycle Number**
 - Identifiler Plus (**29 cycles and 32 cycles**; 28 for 1 ng)
 - PowerPlex 16 HS (**31 cycles and 34 cycles**; 30 for 1 ng)

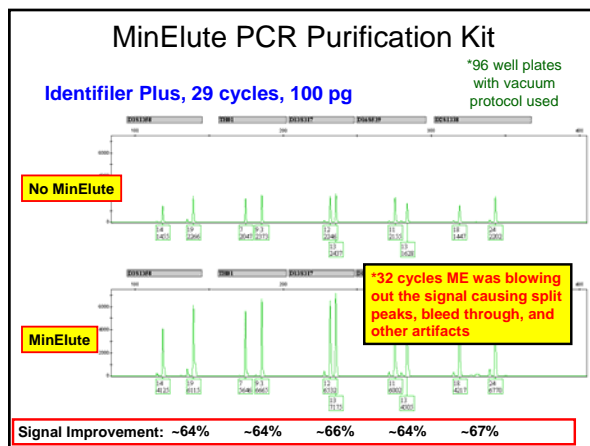
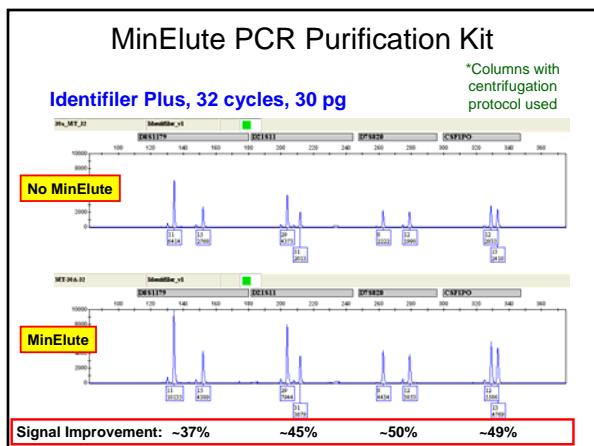


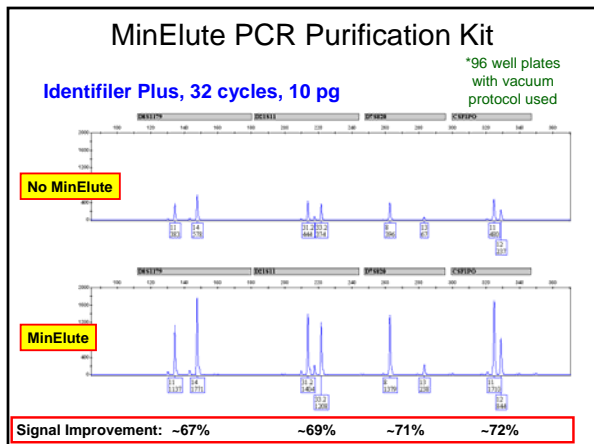
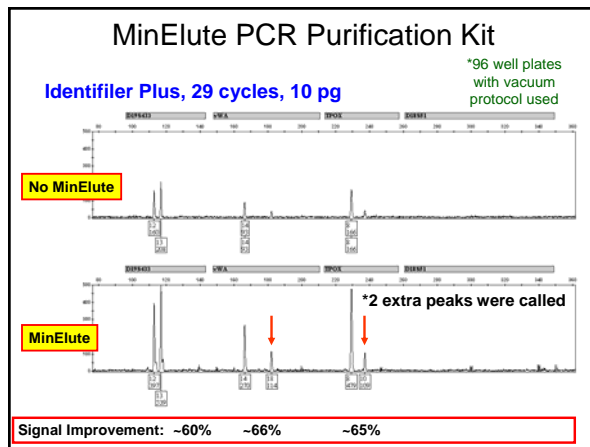
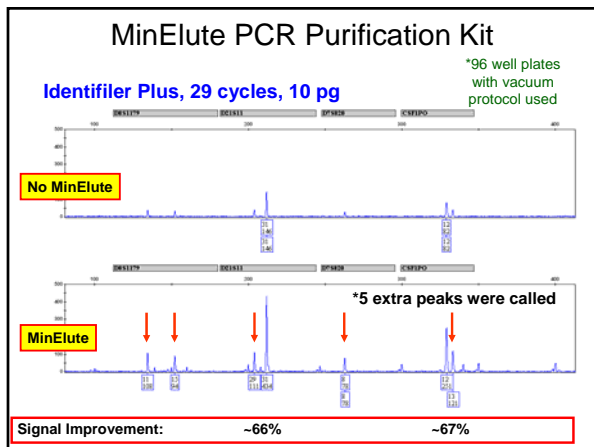
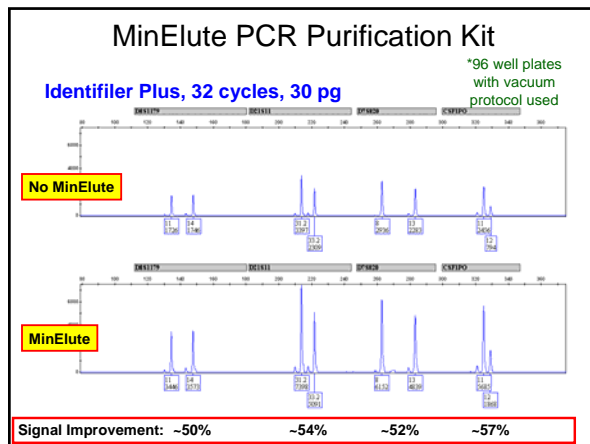
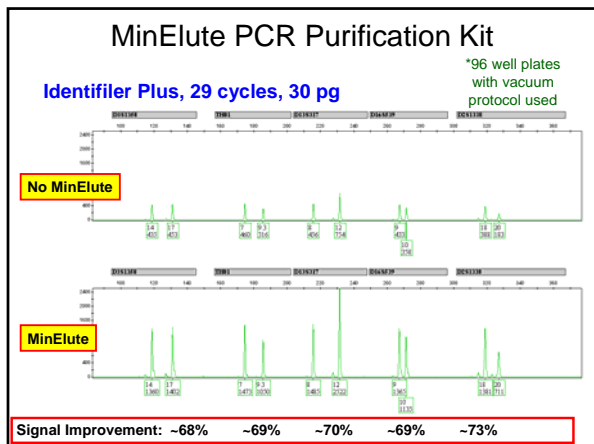






- ### Additional Methods of LT-DNA Testing and Future Studies at NIST
- Signal enhancing techniques
 - MinElute PCR purification kit (Qiagen) for salt removal in final product – **results shown**
 - Increasing CE injection voltage and time
 - Reduced volume PCR (concentrates amplicon)
 - Degraded DNA studies
 - LT-DNA mixture studies





- ### Conclusions
- The results with pristine full heterozygous samples demonstrate that replicate testing can produce reliable information with single source samples at low levels of DNA when consensus profiles are created.
 - Identifiler Plus with 32 cycles and PowerPlex 16 HS with 34 cycles were comparable in performance with low-level DNA analysis.
 - With 3 extra cycles, there was better recovery at 10 pg of DNA using both kits including less allelic and full locus drop-out. However, there is a greater potential for allele drop-in or high stutter.
 - MinElute PCR Purification Kits were successful in significantly increasing the signal for LT-DNA PCR products and resulted in extra peaks being called at 10 pg DNA samples.

New Section of STRBase on LT-DNA

- Recently launched webpage
 - <http://www.cstl.nist.gov/biotech/strbase/LTDNA.htm>
 - Low-template DNA = LT-DNA
- The LT-DNA section includes:
 - **Presentations from past LT-DNA talks and workshops**
 - **Validation data from our sensitivity studies** to illustrate problems and consensus profile solution to low levels of DNA testing
 - **Literature listing of pertinent articles** to help explain the issues involved in this topic

Publication on Scientific Issues of LT-DNA

The screenshot shows a Promega website page. At the top is the Promega logo and a navigation bar with 'Corporate', 'Products', and 'Resources'. Below the navigation bar, there is a section titled 'Profiles in DNA' with a yellow box indicating 'Published online April 5, 2010'. The article title is 'Scientific Issues with Analysis of Low Amounts of DNA'. The authors are listed as John M. Butler* and Carolyn R. Hill. The affiliation is the National Institute of Standards and Technology, Biochemical Science Division, Gaithersburg, Maryland, USA. A footnote identifies John M. Butler as the corresponding author. At the bottom, a blue line of text states '*Based on LT-DNA studies performed in Fall 2009'.

Acknowledgments

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Points of view are mine and do not necessarily represent the official position or policies of the US Department of Justice or the National Institute of Standards and Technology.

NIST Team for This Work



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Dave Dueser

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